

[Home](#) | [List](#) | [New](#) | [Edit](#) | [Delete](#) | [Reply](#) | [Duplicate](#) | [Find](#) | [Config](#) | [Help](#)

Message ID: **200** Entry time: **Wed Mar 6 13:16:37 2024**

|                   |  |
|-------------------|--|
| Experiment Date:  | 2024 03 06   |
| Duration (Days):  | 3  |
| User:             | Anja Miokovic, Stjepko Fazinic, Iva Bozicevic Mihalic                        |
| Accelerator:      | Tandetron  |
| Beam Line:        | Old uProbe   |
| Project:          | Hi-REXS (HRZZ projekt)   |
| Experiment Title: | HR PIXE Mg compounds: measurements that needed to be repeated and new target |
| Beam:             | 2MeV H, 3 MeV He   |
| Method:           | HR PIXE, PIXE, RBS   |

Chamber positioned according to the black marks on the floor.

Beam deflection was connected to the horizontal deflector with -700 V.

GreatControl: X Binning = OFF, Y Binning = OFF, Readout Speed = 500 kHz, Gain = Max Sensitivity, Correct Bias = UNCHECKED,  $T_{\text{ccd}} = -70$  °C,  $T_{\text{back}} = 23$  °C, Chiller at 18 °C

PIXE: Coarse gain=1 k; Fine gain=3; Shaping time=2 us; covered with Al (1 mm thick) mask with hole of  $2r=1.7$  mm

RBS: Bias=+50 V; Coarse gain=200; Fine gain=7.08; Shaping time=1 us; covered with teflon mask (3 mm thick) with hole of  $2r=3$  mm

## 6.3.2024.

### Beam: 2 MeV H<sup>+</sup> TDT

Scanning:  $x=10.0$ ,  $y=9.55$

Diffraction crystal: Beryl(1010) on 11.4 cm, peeking out of holder for 4 mm

Samples: MgWO<sub>4</sub>+Ge (2), Mg+Ge (3), MgO+Ge (4), quartz (5), Cu mesh 400 (6)

Ge in mixtures is from Ge detector.

$I \sim 3.2$  nA on metal before measurement

| FILE    | SAMPLE      | DETECTOR      | $t_{\text{exp/s}}$ | $N_{\text{frames}}$ | COMMENT  |
|---------|-------------|---------------|--------------------|---------------------|--|
| 2403001 | Cu mesh 400 | SDD           | /                  | /                   | SS=5x0.1   |
| 2403002 | MgO+Ge      | CCD           | 3                  | 1                   |  |
| 2403003 | DARK        | CCD           | 3                  | 10                  |  |
| 2403004 | MgO+Ge      | CCD, SDD      | 3                  | 20                  | PIXE: $I(\text{GeKa})/I(\text{GeLa}+\text{MgKa}) \sim 0.19$ , in HR-PIXE spectrum Ge is too high   |
| 2403005 | MgO+Ge      | CCD, SDD, SBD | 3                  | 1080                | $I \sim 2.5$ nA; PIXE: $I(\text{GeKa})/I(\text{GeLa}+\text{MgKa}) \sim 0.12$ -> good position  |
| 2403006 | MgO+Ge      | CCD, SDD, SBD | 3                  | 557                 | $I \sim 2$ nA and very unstable  |
| 2403007 | Cu mesh 400 | SDD           | /                  | /                   | SS=5x0.1   |
| 2403008 | Mg+Ge       | CCD           | 3                  | 20                  | PIXE: $I(\text{GeKa})/I(\text{GeLa}+\text{MgKa}) \sim 0.15$ -> in HR-PIXE spectrum we want a little bit higher Ge  |
| 2403009 | Mg+Ge       | CCD           | 3                  | 20                  | PIXE: $I(\text{GeKa})/I(\text{GeLa}+\text{MgKa}) \sim 0.17$ -> good position   |
| 2403010 | DARK        | CCD           | 5                  | 10                  |  |
| 2403011 | Mg+Ge       | CCD, SDD, SBD | 5                  | 1030                | $I \sim 1.5-4$ nA -> very unstable, but then beam was optimized and got more stable: $I \sim 2.5$ nA; with no apparent reason terminal voltage switched off by itself in the middle of the measurement and we had no beam until some specific power supply near TDT was turned on (Željko's instructions on call) -> frames 410-592 have no events; <b>carefully with the analysis: frames with max current should probably be excluded!</b> |

Energy window used in Matlab analysis: [240, 360]

## 7.3.2024.

### Beam: 2 MeV H<sup>+</sup> TDT

Focus: Me 16.5 A; Ox 34.8 A

Scanning: x=10.0, y=9.55

Diffraction crystal: Beryl(1010) on 11.4 cm, peeking out of holder for 4 mm

Samples: MgWO<sub>4</sub>+Ge (2), Mg+Ge (3), MgO+Ge (4), quartz (5), Cu mesh 400 (6)

Ge in mixtures is from Ge detector.

| FILE  | SAMPLE                | DETECTOR      | t <sub>exp</sub> /s | N <sub>frames</sub> | COMMENT   |
|---|-----------------------|---------------|---------------------|---------------------|---|
| 2403012   | Cu mesh 400           | SDD           | /                   | /                   | SS=5x0.1  |
| 2403013   | MgWO <sub>4</sub> +Ge | CCD           | 8                   | 1                   | I~1.5 nA  |
| 2403014   | DARK                  | CCD           | 8                   | 10                  |   |
| 2403015   | MgWO <sub>4</sub> +Ge | CCD, SDD, SBD | 8                   | 328                 | I~1.2-0.8 nA; PIXE: I(WLb+GeKa)/I(WLa)~1.5; measurement stopped because current fell and could not be increased |
| After some time of trying it was not possible to get current higher than 0.8 nA from TDT control. We decided to check if everything is connected as it should be with the deflectors. -> It is all right.<br>As we were checking cables there, Željko came and said that he didn't change any parameter but current suddenly increased to over 3 nA. Is it possible that some contact is bad and that the problem with the low current came because of that?<br>We decided to not touch anything again and continue with the measurement, but contacts should be checked at some point.<br>Andro's slits closed a bit for better focus. |                       |               |                     |                     |   |
| 2403016   | Cu mesh 400           | SDD           | /                   | /                   | SS=5x0.1  |
| 2403017   | MgWO <sub>4</sub> +Ge | CCD, SDD, SBD | 8                   | 544                 | I~2 nA; PIXE: I(WLb+GeKa)/I(WLa)~1  |
| 2403018   | MgWO <sub>4</sub> +Ge | CCD, SDD, SBD | 8                   | 360                 | I~2 nA  |
| 2403019   | MgWO <sub>4</sub> +Ge | CCD, SDD, SBD | 8                   | 180                 | I~2.2 nA  |
| 2403020   | Cu mesh 400           | SDD           | /                   | /                   | SS=5x0.1, checking focus -> still good  |
| 2403021   | MgO+Ge                | CCD, SDD, SBD | 5                   | 520                 | I~2.8-3.2 nA; PIXE: I(GeKa)/I(GeLa+MgKa)~0.13   |
| 2403022   | MgO+Ge                | CCD, SDD, SBD | 5                   | 520                 | -    -; Spector file was not saved because Spector was not stopped before turning off the crate                 |

Energy window used in Matlab analysis: [240, 360]

## 8.3.2024.

### Beam: 3 MeV He<sup>2+</sup> TDT

Focus: Me 20.4 A; Ox 42.9 A

Scanning: x=10.0, y=9.55

Diffraction crystal: ADP on 6 cm, peeking out of holder for 3 mm

Samples: Mg chunk - half clean Mg, half MgO (1), MgWO<sub>4</sub> (2), Mg+Ge (3), MgO+Ge (4), quartz (5), Cu mesh 400 (6)

Ge in mixtures is from Ge detector.

I~1.5 nA on metal before measurement

| FILE    | SAMPLE            | DETECTOR | t <sub>exp</sub> /s | N <sub>frames</sub> | COMMENT  |
|---------|-------------------|----------|---------------------|---------------------|----------|
| 2403023 | Cu mesh 400       | SDD      | /                   | /                   | SS=5x0.1 |
| 2403024 | Mg                | CCD      | 10                  | 1                   |          |
| 2403025 | MgWO <sub>4</sub> | CCD      | 30                  | 1                   | I~0.5 nA |
| 2403026 | DARK              | CCD      | 10                  | 10                  |          |
| 2403027 | MgWO <sub>4</sub> | CCD      | 10                  | 600                 | I~0.8 nA |
| 2403028 | MgWO <sub>4</sub> | CCD      | 10                  | 400                 | I~0.9 nA |